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San José State APS March 2004: K1.189: ENHANCED RESONANT SOFT X-RAY SCATTERING YBa2Cu3O7.x 50 nm THIN FILMS ON BYCRISTALLINE SUBSTRATES

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- Josephson junction: structure consisting of two superconductors called electrodes separated by a thin layer called barrier.

- The barrier coupling the two superconductors can be: insulator (tunnel junctions) or semiconductor, normal metal or alloy, or another superconductor with reduced critical parameters (weak links).

 The current across a high angle grain boundary in YBa₂Cu₃O_{7,x} (YBCO) thin films is several orders of magnitude lower than that of an epitaxial film: behave as a week links or grain boundary Josephson junctions (GBJJs). Fabrication of artificial GBJJs: deposition of the YBCO thin film on bicrystalline substrates.

 Bicrystalline substrates: two single crystals cut at different angles, polished and fused together. A till grain boundary is formed at the interface of the two single crystals. The grain boundary is transferred to the thin film deposited on the bicrystal substrate and the grain boundary is the barrier of the junction.



Figure 1. Bicrystalline substrate

2. MOTIVATION AND OBJECTIVE

- Experimental observations of the grain boundary in YBCO GBJJs: the barrier is a very disordered region.

- The strain fields of dislocations perturb the local structure, mainly in the YBCO oxygen sublattice in the barrier and in the adjacent regions even leading to non - superconducting zones.

 OBJECTIVE: to obtain some compositional information, mainly related to the oxygen content, in different positions along the normal direction to the grain boundary.

3. EXPERIMENTAL

3.1. Samples fabrication - YBCO thin films are grown in a high pressure pure oxygen sputtering system at Applied Physics Department (Complutense University)

- The thickness of the samples fabricated is around 50 nm. The critical temperature for the films is in the range 89.5-91 K.

3.2. XAS measurements

X-Ray absorbance at O_{K-edger} Cu_{L3.2-edges} measured in the back scattering geometry by the enhancement of the YBCO [001] diffraction peak at station 6.3.1 of ALS (J. Kortright endstation)



Figure 2. Experimental geometry The enhanced scattering was measured at a value of θ_{Bragg} on the diffraction tail



Figure 3. Samples on the probe for the experiment components



4. RESULTS AND DISCUSSION

5. CONCLUSSIONS

-Qualitative information of the composition of the YBCO deposited of a bi-crystalline substrate can be obtained from the analysis of the spectra collected in different regions along the grain boundary in the back scattering geometry by the enhancement of the YBCO [001] diffraction peak

-We have deduced that the crystallographic grain boundary is a region mainly deficient in oxygen but this affect to the adjacent regions as well

-Given the symmetry of the FT, the T and x dependence may be discussed for the O_k 1/1₀ in absorption. This is not true for the Cu₁₂₃ and Ba₃₄₄₅ edges where the FT indicate mixture of the real and imaginary be for the experiment